

产品规格书

SPECIFICATIONS FOR PRODUCT

产品类型 TYPE : Quartz Crystal

产品规格 SPEC : 32.768KHz/8038/12.5PF/20PPM

产品型号 P/N : CJK04-327681220B20

日期 DATE : 2022/01/18

核准及签名			者をプロ
R&D APPR. SIGNATURED			DEPT.
拟制	审核	批准	频率器件事业部
ISSUE	CHECK	APPROVAL	
Ivan 2022/01/18	Abbey 2022/01/18	Ken 2022/01/18	

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JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD.

SMD CJ-306 Quartz Crystal

CJK04-327681220B20

1. Scope:

1.1 This specification applies to the RoHS/SONY compliance quartz crystal unit with a frequency of 32.768KHz which will be used in crystal oscillator applications.

2. Construction:

2.1 Type of Quartz Resonator: CJ-306

3. Electrical Characteristics

3.1 Mode of Vibration:	+2°X-cut , Fundamental
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3.2 Nominal frequency(F): 32.768KHz

3.3 Load Capacitance(CL): 12.5 PF

3.4 Frequency Tolerance at 25°C ±20ppm

3.5 Series Resistance(Rr): 60 ΚΩ Max

3.6 Quality Factor(Q): 60K TYP

3.7 Turnover Temperature(To): 25 $^{\circ}\text{C} \pm 5^{\circ}\text{C}$

3.8 Temperature Coefficient(K): -0.035±0.006 ppm/°C²

3.9 Operation Temperature: -40 ℃~ +85℃

3.10 Preservation Temperature: -55 °C ~ +125 °C

3.11 Shunt Capacitance(Co): 1.5PF Typical

3.12 Aging 1st Year($\triangle f / f$): ±5 ppm max.

3.13 Shock Resistance: ±5 ppm max.

3.14 Capacitance Ratio(C₀/C₁): 520 Typical

3.15 Insulation Resistance: 500MΩ at DC 100V±15V

3.16 Drive Level: 1 µ W

Reliability Specifications

4. Reliability Specifications

This is the quality control and quality assurance and reliability tests performance data for the RoHS/SONY compliance 32.768KHz CJ-306 Quartz Crystal.

related to the specification and approval sheet provided by JSCJ.

Standard test condition (TEMP.: 20±5°C. Relative humidity: 65±20%)

For any discrepancy in GO/NG, test will be done at TEMP.25±2°C, R.H. 65±5%.

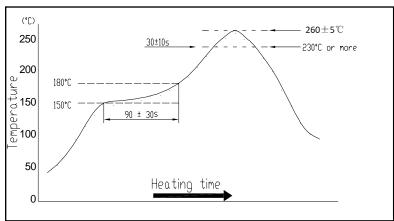
NO.	PROCESS	SPECIFICATION	TEST METHOD
4.1	Temperature Cycle (GB/T 2423.22-2002, Method Nb)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	10 cycles from -55°C to 125°C. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.2	Low Temperature Storage (GB/T 2423.1-2001, Method Aa)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 72 hrs at -55°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.3	High Temperature Storage (GB/T 2423.2-2001, Method Ba)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 72 hrs at 125°C±3°C constant temperature. Measurement taken after DUT being left at room temperature for 24±2 hours.
4.4	Humidity (GB/T 2423.3- 2006, Method Cab)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Spending 96 hrs at 40 °C \pm 3 °C, with 93 %R.H, Then keep the DUT in dry oven at 40 \pm 5 °C for 24 hour. Measurement taken after DUT being left at room temperature for 1 to 2 hours.
4.5	Vibration (GB/T 2423.10- 1995, Method Fc)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Apply 0.75mm vibration at sweep frequency $10\sim$ 500 Hz, 10 cycles in each direction of 3 axis. Measurement taken after 1 hour.
4.6	Shock (GB/T 2423.5-1995, Method Ea)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.and exhibit no visible damage.	Peak 1000m/s2, normal width 6ms half sine wave form, 3.7m/s, 3 perpendicular axis of samples, 3 cycles / direction, total 18 cycles. Measurement taken after 1 hour.
4.7	Drop (GB/T 2423.8-1995, Method Ed)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.and exhibit no visible damage.	Free drop to the steel plate with thickness of 3 mm from 0.75 m heights for 3 times.
4.8	Solderability (IEC60068-2-58,Test Td:)	Terminals shall be covered more then 95% with solder.	Passed through the re-flow oven under the following condition. Preheat 150 to 180°C for 60 to 120sec, and soldering time for 20s ± 5s at 235°C, peak soldering time for 10s ± 1s betweein 240 and 250°C. There is no need to do functional test. 8-12X magnifier.
4.9	Terminal Strength (JIS-C-6429 Method 1 & 2)	No visible damage	Mount on a glass-epoxy board (100x50x1.6mm), then bend to 2mm displacement (velocity 1mm/sec) and keep for 5 seconds. or pulling force 0.5kg for at least 60 seconds.
4.10	Resistance to Soldering Heat (IEC60068-2-58,Test Td: Table 4)	Frequency change after test ≤± 5ppm.Resonance resistance change after test ≤10ohms.	Passed through the re-flow oven under the following condition. Preheat 150 to 180°C for 60 to 120sec, and sodering time for 60s max at 235°C, peak soldering time for 20s max at 265°C max. Measurement taken after DUT being left at room temperature for at least 2 hours.
4.11	OTHERS		

Recommended Reflow soldering condition

5. Recommended Reflow soldering condition (SMD)

Solder profile

Peak: 260±5 $^{\circ}$ Soldering zone: 230 $^{\circ}$ or more, 30±10s. Pre-heating zone 1: 150 $^{\circ}$ 180 $^{\circ}$, 90±30s



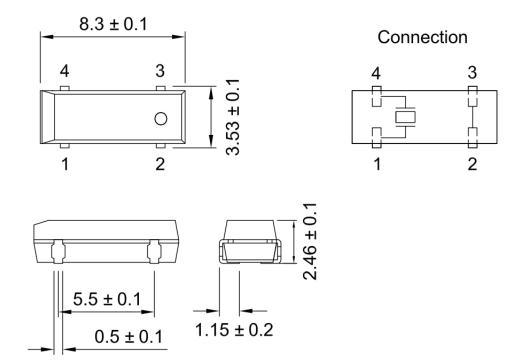
Temperature profile for reflow soldering

6. Soldering iron method

Bit temperature: $350\pm10^{\circ}$ C Application time of soldering iron:3+1 s. For other procedures, refer to IEC 60068-2-20.

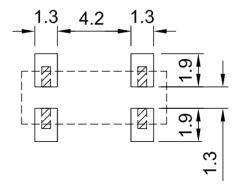
Package Outline Dimensions

Units:mm



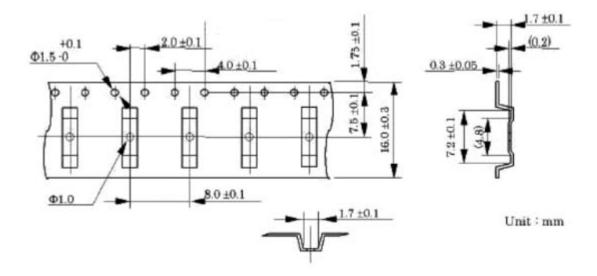
Suggested Pad Layout

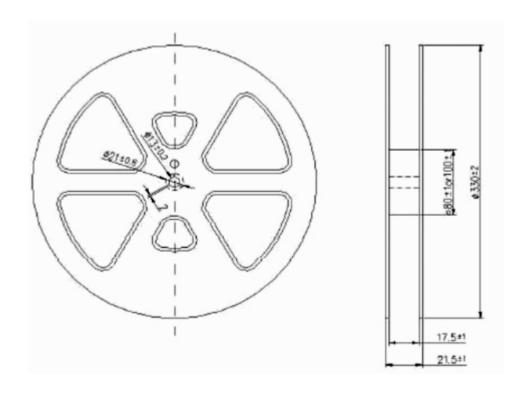
Suggested Layout



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